



Silicon **C**arbide Detectors
for **I**ntense **L**uminosity **I**nvestigations and **A**pplications

European Nuclear Physics Conference 2018

Salvo Tudisco

02-07 September 2018 *Bologna, Italy*

Why Silicon Carbide for radiation detection

Property	Diamond	GaN	4H SiC	Si
E_g [eV]	5.5	3.39	3.28	1.12
$E_{breakdown}$ [V/cm]	10^7	$4 \cdot 10^6$	$3-4 \cdot 10^6$	$3 \cdot 10^5$
μ_e [cm^2/Vs]	1800	1000	800	1450
μ_h [cm^2/Vs]	1200	30	115	450
v_{sat} [cm/s]	$2.2 \cdot 10^7$	-	$2 \cdot 10^7$	$0.8 \cdot 10^7$
Z	6	31/7	14/6	14
ϵ_r	5.7	9.6	9.7	11.9
e-h energy [eV]	13	8.9	7.6-8.4	3.6
Density [g/cm ³]	3.515	6.15	3.22	2.33
Displacem. [eV]	43	≥ 15	30-40	13-15

- Wide band-gap (3.3eV)
- ⇒ Visible blind
- ⇒ Lower Leakage current

- High Breakdown
- ⇒ Advantage for Radiations hardness

- Different e-h mobility
- ⇒ Charge Identification pulse shape analysis

- Fast devices
- ⇒ Timing applications

- Signal
- ⇒ Less charge than Si, $SiC \approx Si/2$
- ⇒ A problem for MIP!
 - Diamond 36 e/ μm
 - SiC 51 e/ μm
 - Si 89 e/ μm
- ⇒ No problem in all other case

- Higher displacement threshold
- ⇒ Radiation harder than Silicon

Applications

- UV - Soft-X detection
- Charged Particle detection and identification
- Neutron detection



Radiation Hard detectors for Nuclear Physics experiments and Nuclear applications

Call GRV-INFN

SiCILIA strategy →



Epitaxial growth SIC: beyond the state of the art (small number of defects) →



New Tecnology

→ Schottky junctions



FONDAZIONE
BRUNO KESSLER

→ p-n junctions →



STMicroelectronics

Participating INFN research units

INFN Laboratori Nazionali del Sud di Catania (LNS)

INFN Sezione di Catania and "Gruppo collegato di Messina" (CT-ME)

INFN Sezione di Milano Bicocca (MI-B)

INFN Sezione di Milano (MI)

INFN Sezione di Firenze (FI)

INFN Sezione TIFPA (TN)

INFN Sezione Pisa (PI)

External institutions

CNR-IMM – Catania

CNR-INO – Pisa

PSI – Switzerland

ENEA- Frascati

Companies

Fondazione Bruno Kessler (FBK) – Trento

ST Microelectronics – Catania

LPE – Catania (LPE)



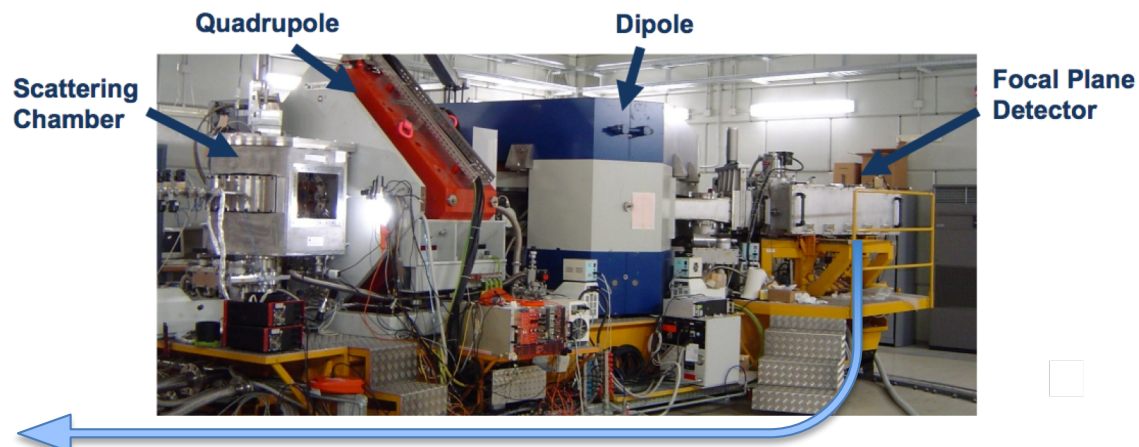
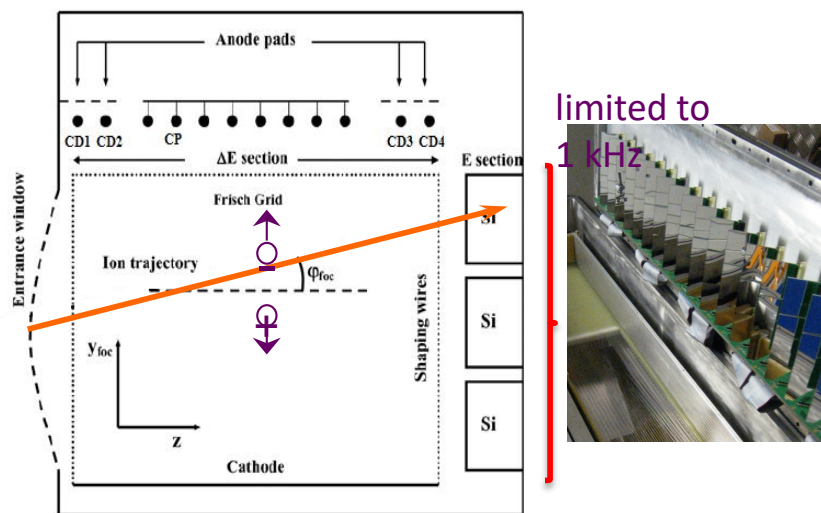
NUMEN project

NUclear Matrix Elements of Neutrinoless Double Beta Decays by Heavy Ion Double Charge Exchange Reactions

DCE => ^{12}C , ^{18}O , ^{20}Ne to energies between 15 and 30 MeV/u

MAGNEX

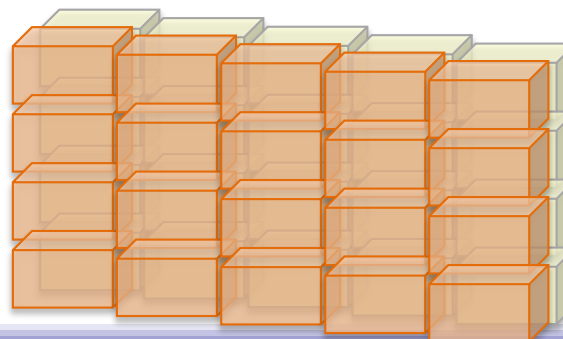
Multiwire gas tracker and ΔE stage



From Multiwire gas tracker → to GEM gas tracker
 From 7 X 5 cm² silicon Wall → to 1 cm² telescopes wall

F. Cappuzzello et al. EPJ A 54 Iss. 5 n. 72 (2018)

R. H. → 10^{14} ions/cm²
 in ten years of activity
 (Si detector dead @ 10^9 implanted ions/cm²)



1 cm² ΔE -E telescope



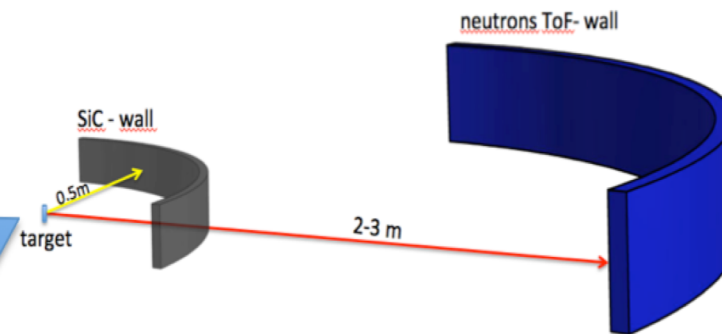
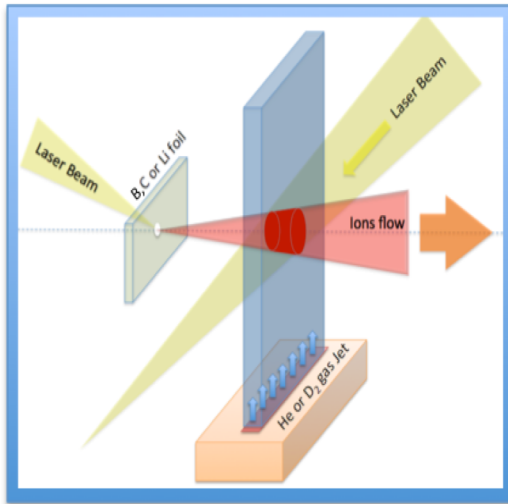
Detectors working in plasmas environment →

Requirements

- ✓ Radiation Hardness
- ✓ Timing
- ✓ Insensitivity to the visible radiation
- ✓ X-ray sensitivity

NuReLP project

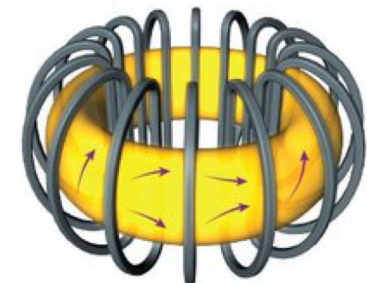
Nuclear Reactions in Laser Plasmas



F. Negoita et al. Rom. Rep. in Phys. Vol. 68 (2016) S37-S144

Applications

- ✓ ELIMED-diagnostic
- ✓ High temperature X-Ray spectroscopy (Space applications...)
- ✓ Neutrons detection (Reactors, Tokamaks...)
- ✓ Dosimetry, beam diagnostic and medical Imaging



Defects in Silicon Carbide

Macroscopic defects

- polytype inclusions
- micropipes
- comets, carrots

Microscopic defects

- dislocations
- stacking faults
- interstitial, vacancies
- divacancies, antisites

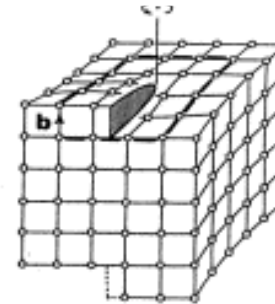
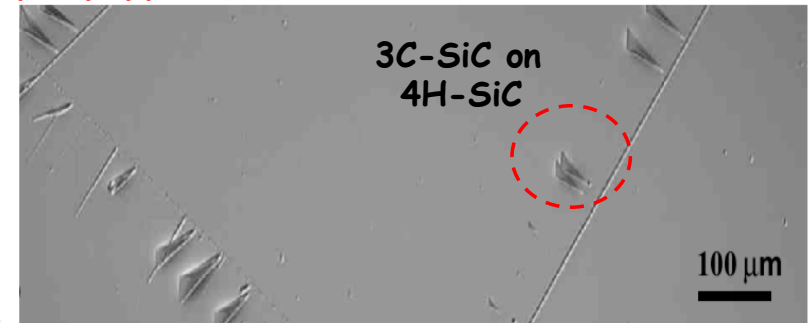


Extended defects

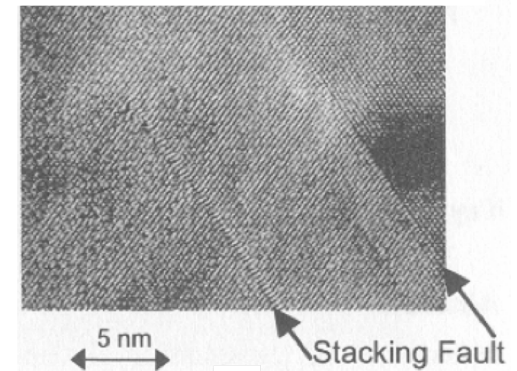
Micro-pipe



polytype inclusions

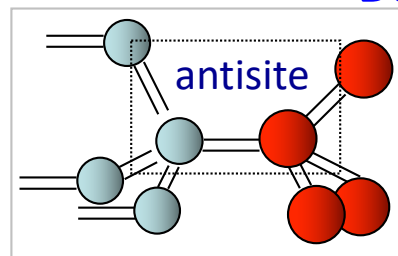
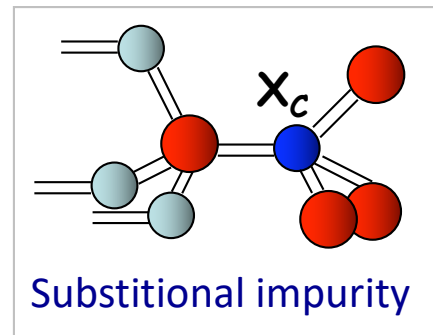
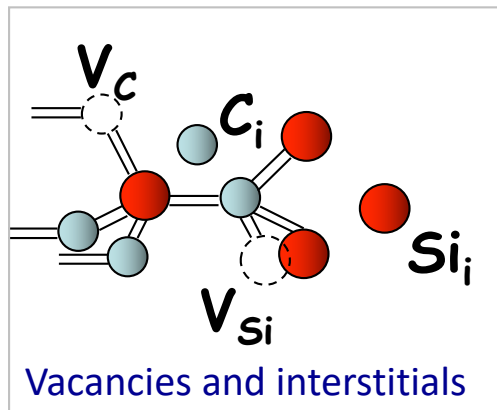


dislocations



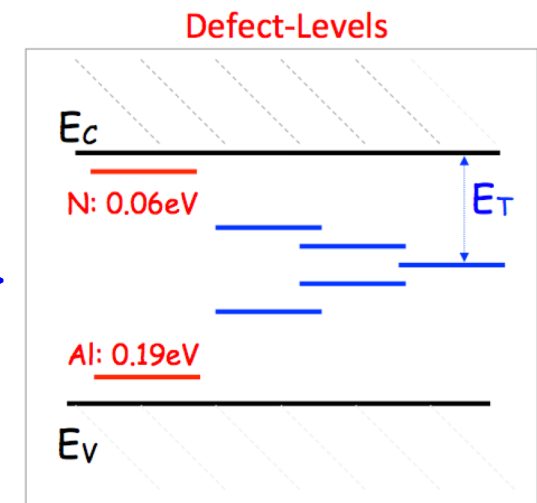
Stacking Fault

Point and Point-like defects

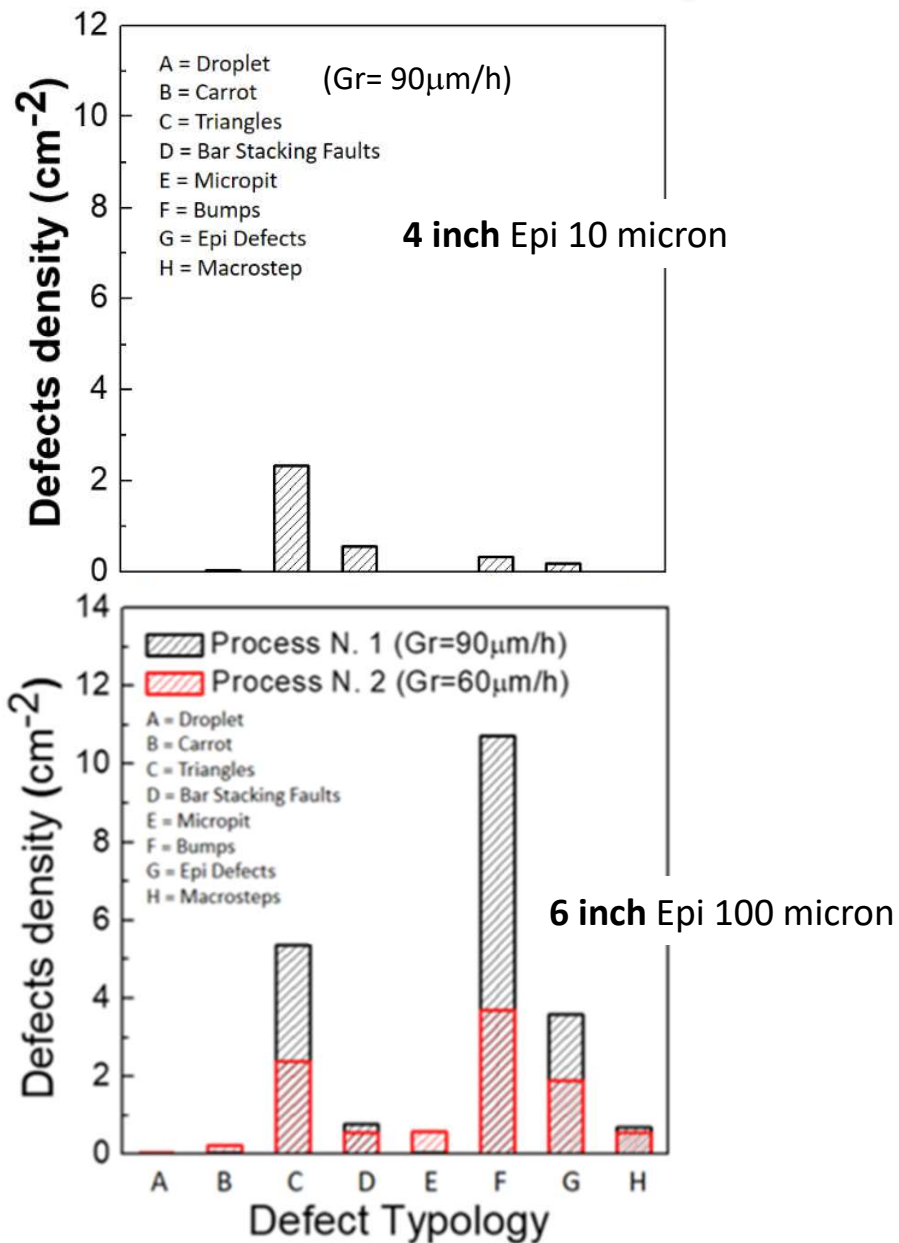


Donor & Acceptor Impurities

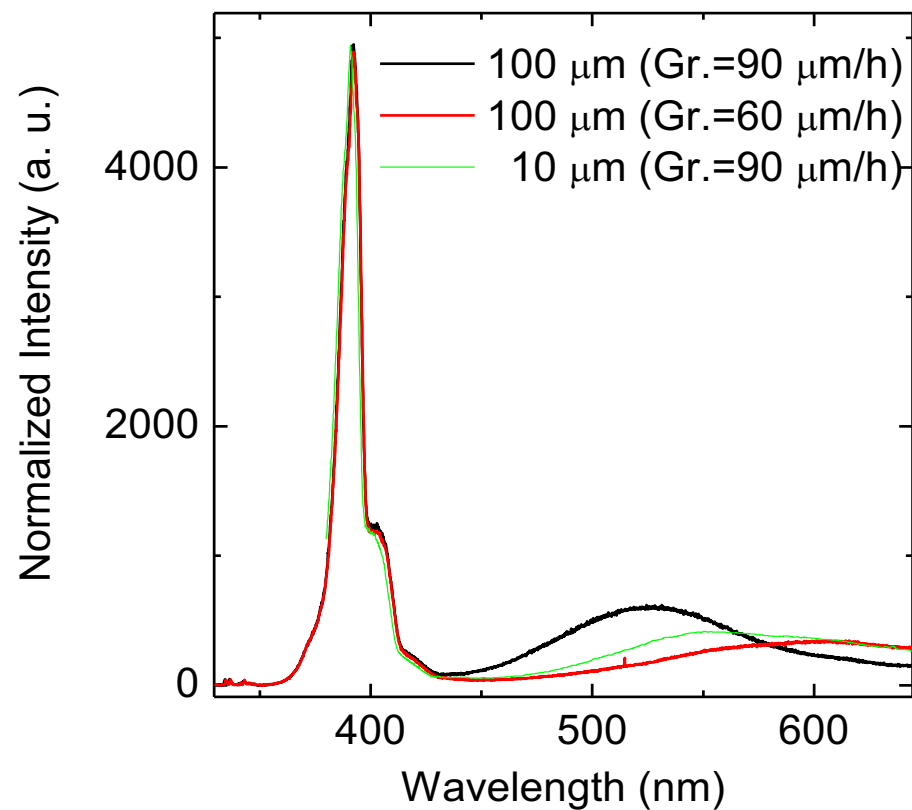
Deep levels in the gap =>



Epitaxial growths



Micro-photoluminescence analysis



S. Tudisco et al. SENSORS Vol. 18 (2018) 2289

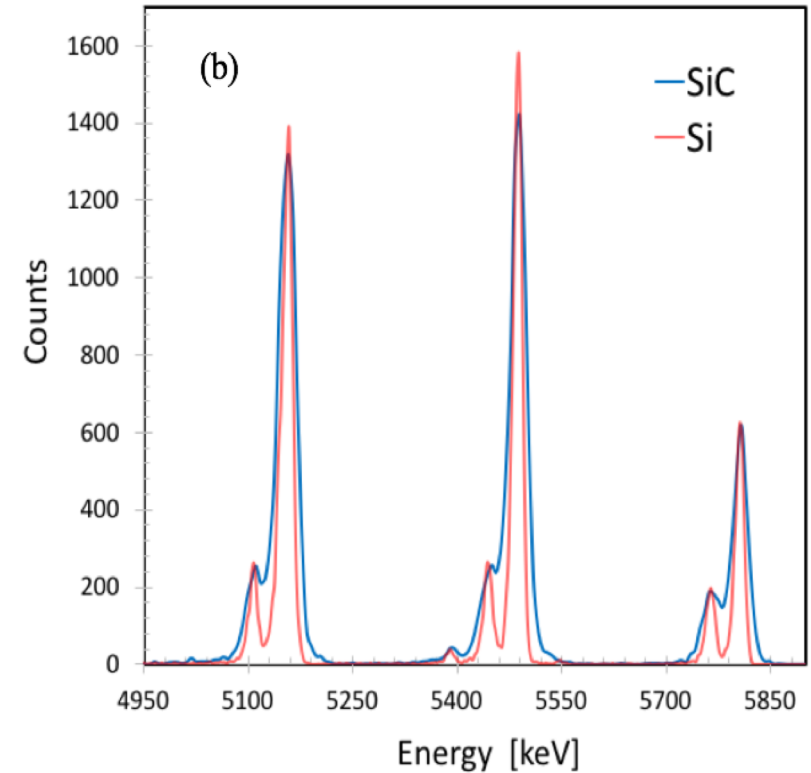
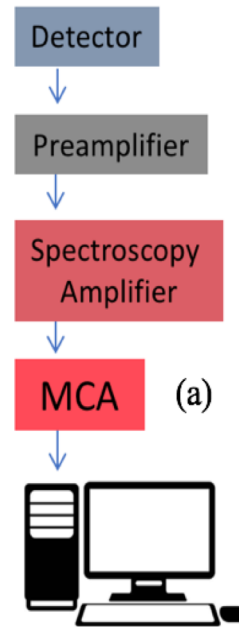
Energy Resolution

Test => Radioactive ^{241}Am Alpha source

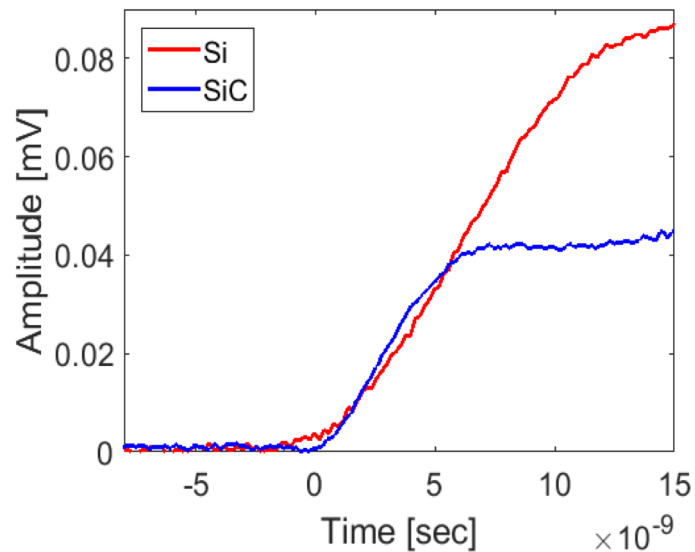
SiC => 42.8 keV FWHM (37.9 keV)

Si => 21.4 keV FWHM (17.1 keV)

Electronic Noise \uparrow

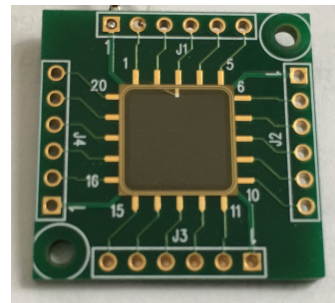


Timing

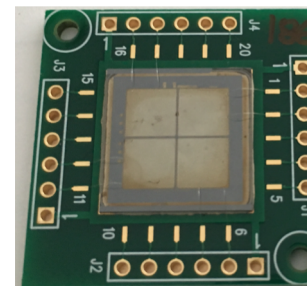


SiC ~ 2 ns

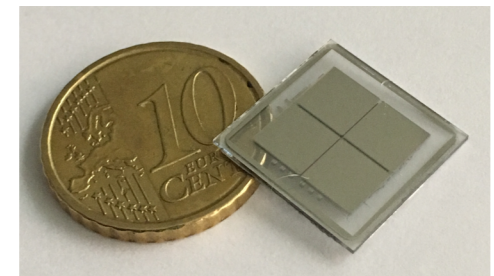
Prototypes



10µm 10x10 mm²



100µm 4 pad da 5x5 mm²



500µm 4 pad 5x5 mm² Intrinsic

Radiation Hardness

Protons beam irradiation



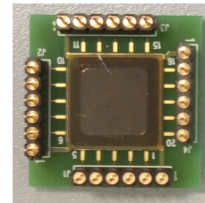
60 MeV H⁺



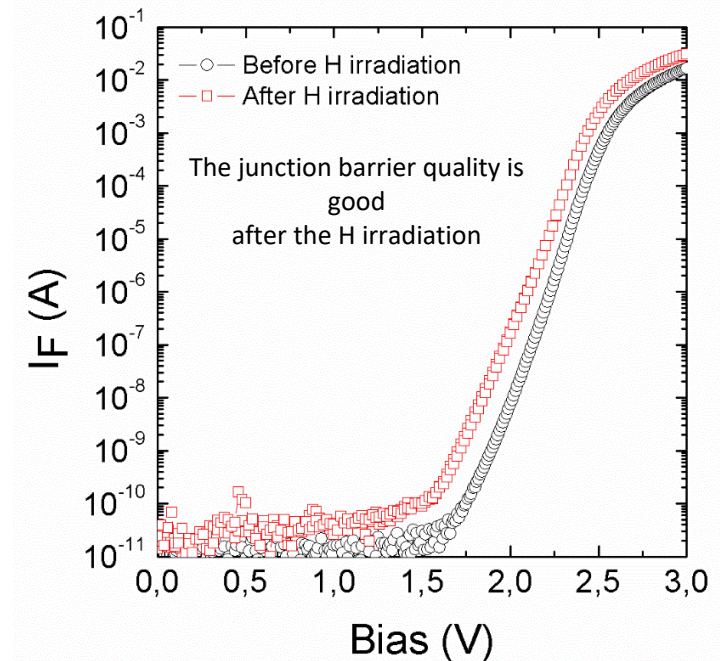
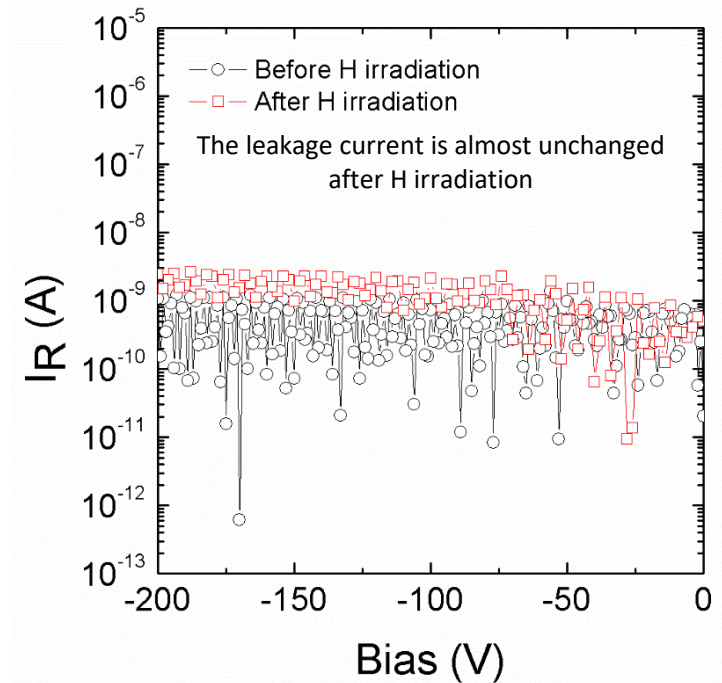
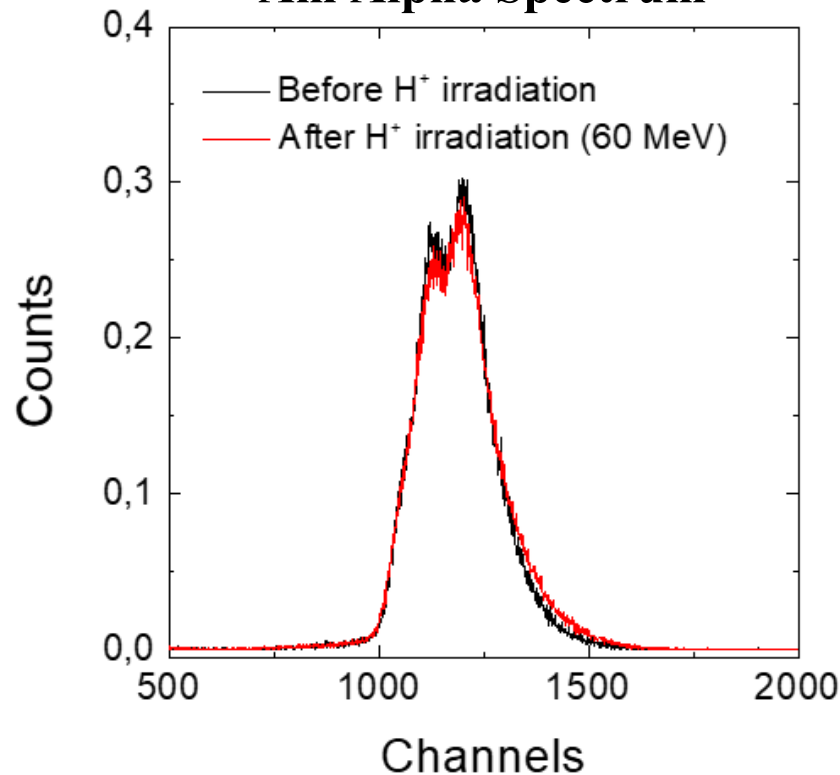
SiC 10 μ m 1x1 cm²

2KGy (2.5 x 10¹² H⁺/cm²)

LNS CATANA line



²⁴¹Am Alpha Spectrum

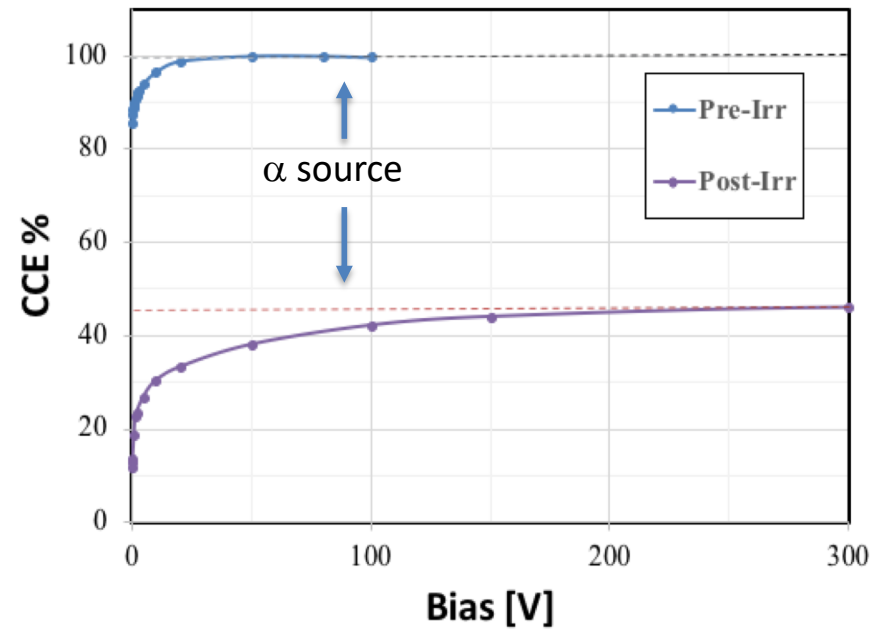
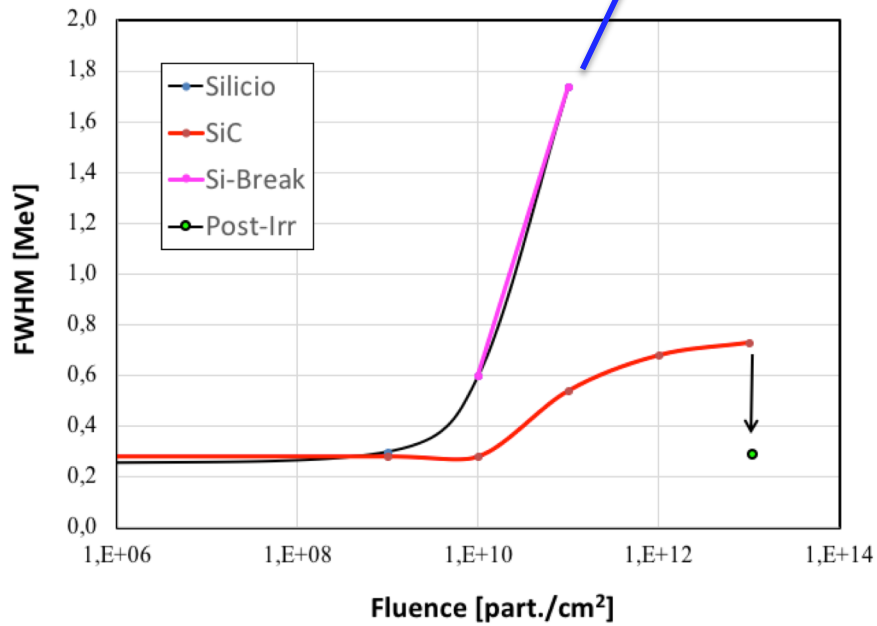
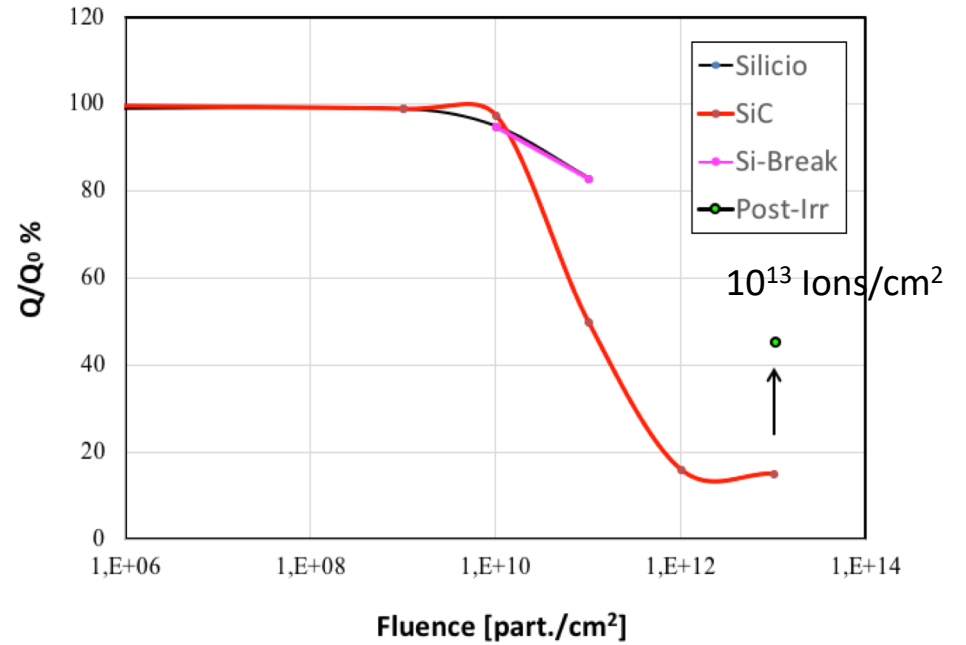
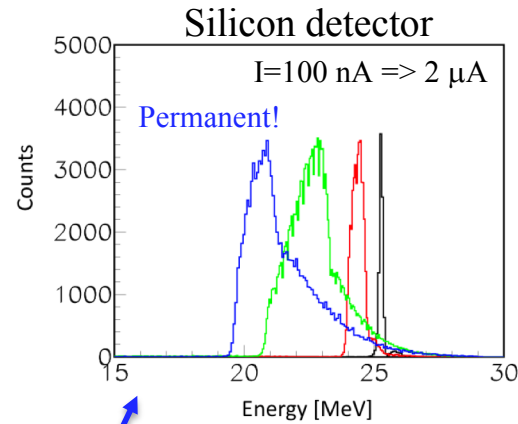
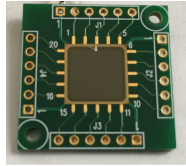


Radiation Hardness

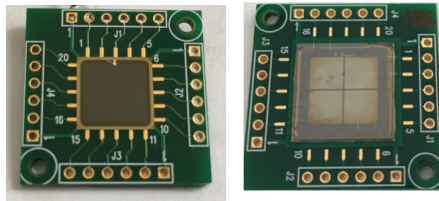
^{16}O 15 MeV



SiC $10\mu\text{m}$ $5\times 5\text{ mm}^2$



Telescope configuration

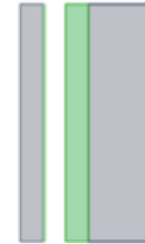


10 μm

100 μm

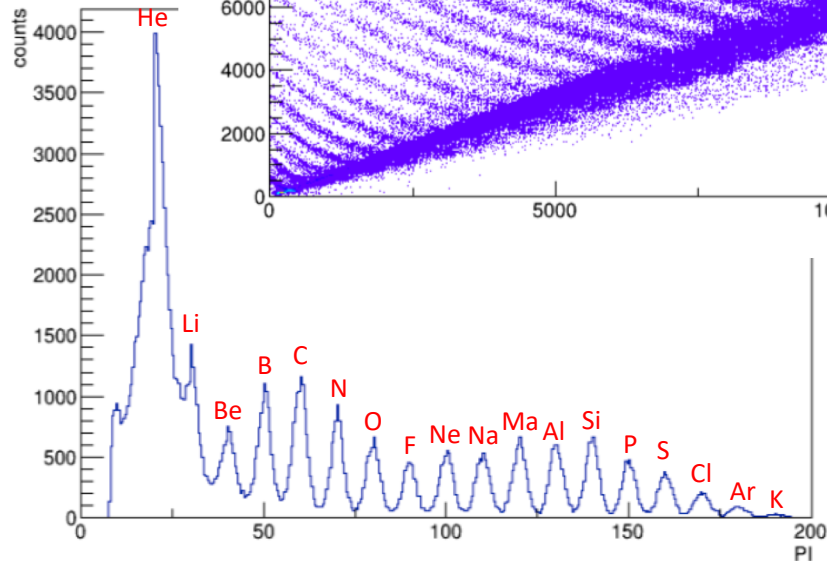
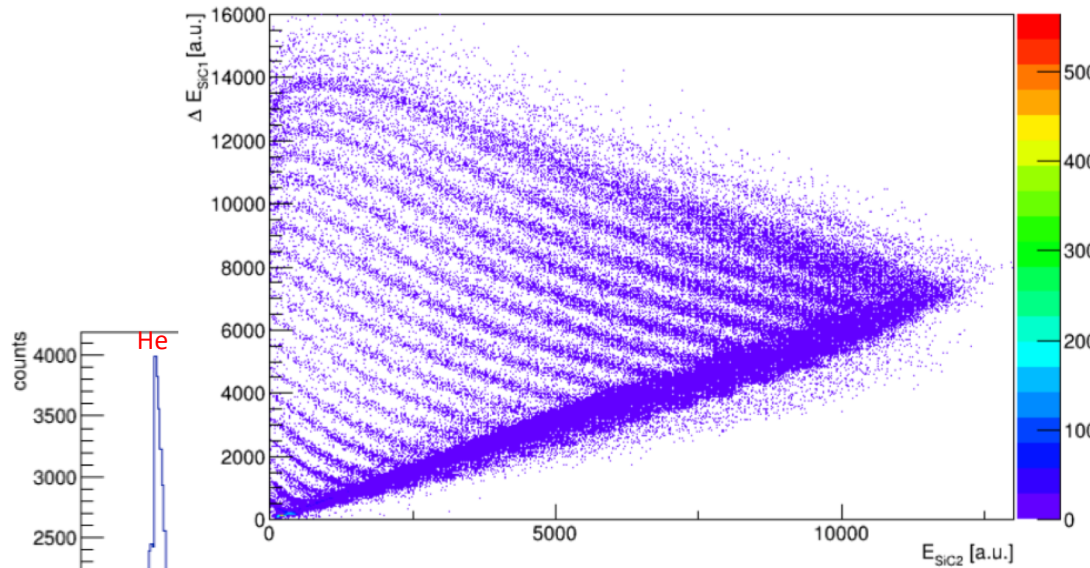


$^{48}\text{Ca} + ^{12}\text{C}$ at 25 MeV/n \rightarrow

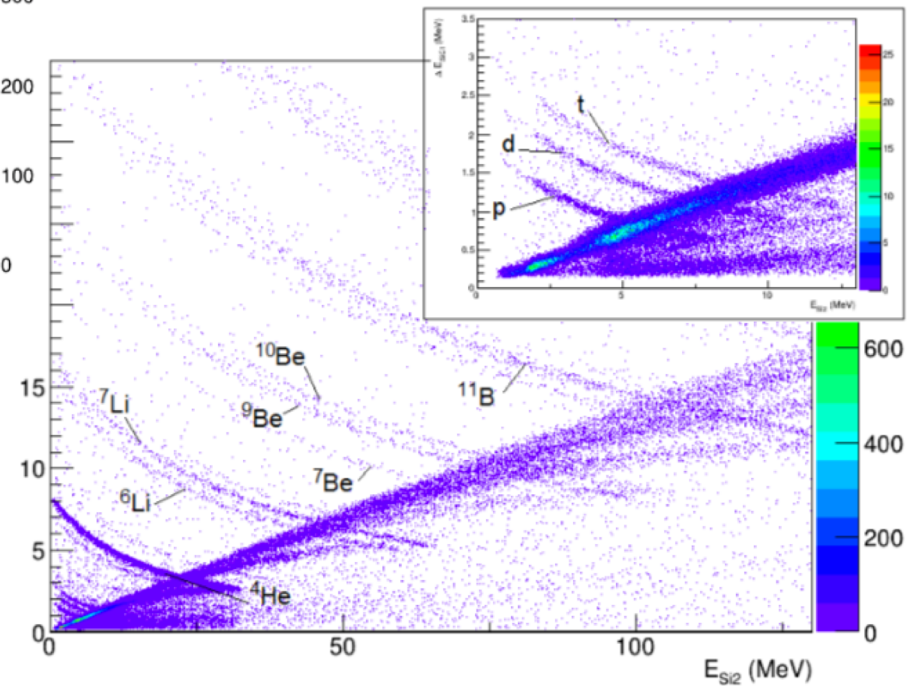


Stage 1
 $^{181}\text{-SiC1}$
 100 μm dead layer
 +
 10 μm SiC

Stage 2
 $^{181}\text{-SiC2}$
 100 μm SiC
 +
 300 μm dead layer



Particle Identification after Linearization



SiCILIA Collaboration

Salvatore Tudisco¹,
Francesco La Via^{1,2}
Clementina Agodi¹
Carmen Altana¹
Giacomo Borghi³
Maurizio Boscardin³
Giancarlo Bussolino⁹
Lucia Calcagno⁴
Massimo Camarda⁵
Francesco Cappuzzello^{1,4}
Diana Carbone¹
Salvatore Cascino⁶
Giovanni Casini⁷
Manuela Cavallaro¹
Caterina Ciampi^{7,13}
Giuseppe Cirrone¹
Giacomo Cuttone¹
Alberto Fazzi⁸
Dario Giove⁸
Giuseppe Gorini⁷
Luca Labate⁹
Gaetano Lanzalone^{1,10}

Grazia Litrico¹¹
Giuseppe Longo⁶
Domenico Lo Presti⁴
Marco Mauceri¹¹
Roberto Modica⁶,
Maurizio Moschetti⁶
Annamaria Muoio¹
Franco Musumeci^{1,4}
Gabriele Pasquali^{7,13}
Giada Petringa^{1,4}
Nicolò Piluso⁶
Giacomo Poggi^{7,13}
Stefania Privitera²
Sebastiana Puglia¹
Valeria Puglisi⁶
Marica Rebai⁷
Sabina Ronchin³
Antonello Santangelo⁶
Andrea Stefanini^{7,13}
Antonio Trifirò¹²
Massimo Zimbone²



- ¹ INFN-LNS
- ² IMM-CNR, VIII Strada, 5, 95121 Catania, Italy
- ³ TIFPA-INFN
- ⁴ INFN-Catania and Phys. Depart. of Catania
- ⁵ Paul Scherrer Institute, Switzerland
- ⁶ STMICROELECTRONICS
- ⁷ INFN-FIRENZE
- ⁸ INFN-MILANO and Dept. of Energy, Politec. Milano
- ⁷ INFN-MILANO BICOCCA and Phys. Depart. of Bicocca University
- ⁹ INO-CNR, via G. Moruzzi 1, 56124 Pisa, Italy
- ¹⁰ UNI-KORE, ENNA UNIVERSITY
- ¹¹ LPE, growing technology Catania
- ¹² MIFT Dept. of Messina University
- ¹³ Phys. Depart. of Firenze University